

N-channel TrenchMOS standard level FET Rev. 02 — 26 January 2011

Product data sheet

Suitable for standard level gate drive

Suitable for thermally demanding environments due to 175 °C rating

Motors, lamps and solenoids

sources

Product profile 1.

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance
- 1.3 Applications
 - 12 V and 24 V loads
 - Automotive and general purpose power switching

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	55	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	18	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	51	W
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 10 A; T_j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	154	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A};$ T _j = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	65	77	mΩ
Avalanche	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\begin{split} I_D &= 6 \text{ A}; V_{sup} \leq 55 \text{ V}; \\ R_{GS} &= 50 \Omega; V_{GS} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split}$	-	-	36	mJ



N-channel TrenchMOS standard level FET

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
2	D	drain	mb	D
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT428 (DPAK)	

3. Ordering information

Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
BUK7277-55A	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

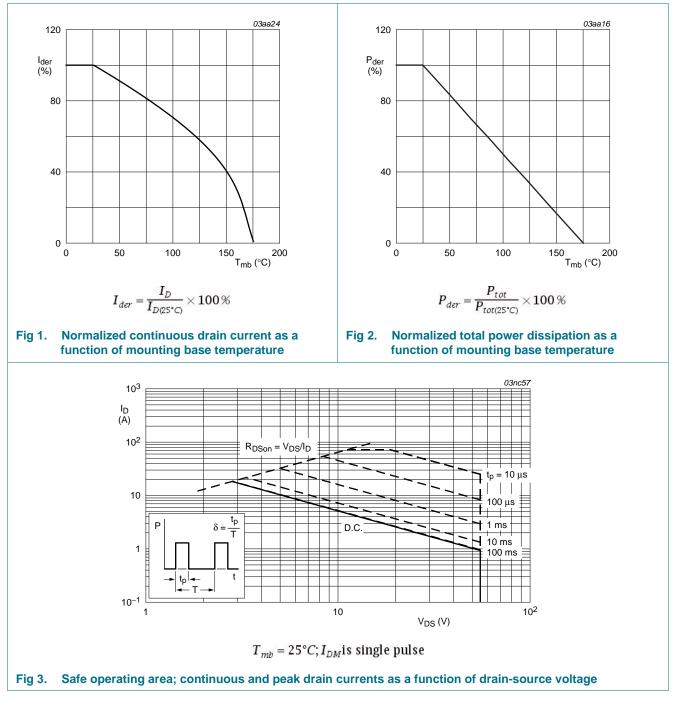
Parameter	Conditions		Min	Max	Unit
drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	55	V
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	55	V
gate-source voltage			-20	20	V
drain current	T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	13	А
	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 3}};$		-	18	А
peak drain current	$T_{mb} = 25 \text{ °C}; \text{ pulsed}; t_p \le 10 \mu\text{s}; $ see Figure 3	1	-	73	А
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	51	W
storage temperature			-55	175	°C
junction temperature			-55	175	°C
diode					
source current	T _{mb} = 25 °C		-	18	А
peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$		-	73	А
ggedness					
non-repetitive drain-source avalanche energy	I _D = 6 A; V _{sup} ≤ 55 V; R _{GS} = 50 Ω; V _{GS} = 10 V; T _{i(init)} = 25 °C; unclamped		-	36	mJ
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source	$\begin{array}{ll} \text{drain-source voltage} & \text{T}_{j} \geq 25 \ ^{\circ}\text{C}; \ \text{T}_{j} \leq 175 \ ^{\circ}\text{C} \\ \text{drain-gate voltage} & \text{R}_{GS} = 20 \ \text{k}\Omega \\ \text{gate-source voltage} \\ \text{drain current} & \frac{\text{T}_{mb} = 100 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}{\text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}; \\ \text{see Figure 3} \\ \text{peak drain current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \text{pulsed}; \ \text{t}_{p} \leq 10 \ \text{\mu}\text{s}; \ \begin{array}{c} \text{I} \\ \text{see Figure 3} \\ \text{storage temperature} \\ \text{junction temperature} \\ \text{junction temperature} \\ \text{diode} \\ \text{source current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{peak source current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{peak source current} & \text{pulsed}; \ \text{t}_{p} \leq 10 \ \text{\mu}\text{s}; \ \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{ggedness} \\ \text{non-repetitive drain-source} & \text{I}_{D} = 6 \ \text{A}; \ \text{V}_{sup} \leq 55 \ \text{V}; \ \text{R}_{GS} = 50 \ \Omega; \\ \end{array}$	$\begin{array}{ll} drain-source \ voltage & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} \\ drain-gate \ voltage & R_{GS} = 20 \ \text{k}\Omega \\ \\ gate-source \ voltage & \\ drain \ current & \frac{T_{mb} = 100 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}{T_{mb} = 25 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}; \\ \\ see \ Figure \ 3 & \\ total \ power \ dissipation & T_{mb} = 25 \ ^{\circ}\text{C}; \ pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ \ 11 \\ \\ \text{see Figure 3} & \\ total \ power \ dissipation & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} & \\ \\ storage \ temperature & \\ \\ \hline \textbf{diode} & \\ \\ \text{source \ current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ peak \ source \ current & T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ peak \ source \ current & pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ \hline \textbf{ggedness} & \\ \\ \text{non-repetitive \ drain-source} & I_{D} = 6 \ \text{A}; \ V_{sup} \leq 55 \ \text{V}; \ R_{GS} = 50 \ \Omega; \\ \end{array}$	$\begin{array}{cccc} drain-source voltage & T_j \geq 25 \ ^{\circ}\text{C}; \ T_j \leq 175 \ ^{\circ}\text{C} & - \\ \\ drain-gate voltage & R_{GS} = 20 \ \text{k}\Omega & - \\ \\ gate-source voltage & -20 \\ \\ drain current & T_{mb} = 100 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1} & - \\ \\ \hline T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}; \\ \text{see Figure 3} & - \\ \\ peak \ drain \ current & T_{mb} = 25 \ ^{\circ}\text{C}; \ pulsed; \ t_p \leq 10 \ \mu\text{s}; \ \ \ 11 & - \\ \\ \text{see Figure 3} & - \\ \\ \text{total power dissipation} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} & - \\ \\ \text{storage temperature} & -55 \\ \\ \text{junction temperature} & -55 \\ \\ \hline \textbf{diode} & & \\ \\ \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ \text{peak source current} & T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ pulsed; \ t_p \leq 10 \ \mu\text{s}; \ T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ \hline \textbf{ggedness} & & \\ \\ \text{non-repetitive drain-source} & I_D = 6 \ \text{A}; \ \text{V}_{sup} \leq 55 \ \text{V}; \ \text{R}_{GS} = 50 \ \Omega; & - \\ \end{array}$	$\begin{tabular}{ c c c c } \hline T_j &\geq 25 \ {}^\circ\mbox{C}; \ T_j &\leq 175 \ {}^\circ\mbox{C} & - & 55 \\ \hline drain-gate voltage & $R_{GS} &= 20 \ k\Omega & - & 55 \\ \hline gate-source voltage & -20 & 20 \\ \hline drain current & $T_{mb} &= 100 \ {}^\circ\mbox{C}; \ V_{GS} &= 10 \ V; \ see \ Figure 1 & - & 13 \\ \hline $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ V_{GS} &= 10 \ V; \ see \ Figure 1; & - & 18 \\ \hline see \ Figure 3 & - & 18 \\ \hline peak \ drain \ current & $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ pulsed; \ t_p &\leq 10 \ \mu s; & $$11$ & - & $$73$ \\ \hline total \ power \ dissipation & $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ see \ Figure 2 & - & $$51$ \\ \hline storage \ temperature & -55 & 175$ \\ \hline junction \ temperature & -55 & 175$ \\ \hline diode & -55 & $$175$ \\ \hline diode & -55 & $$175$ \\ \hline diode & -55 & $$175$ \\ \hline peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$73$ \\ \hline ggedness & $$non-repetitive \ drain-source & $$I_D &= $6 \ A; \ V_{sup} &\leq 55 \ V; \ R_{GS} &= $50 \ \Omega; & $-$ & $$36$ \\ \hline \end{tabular}$

[1] Peak drain current is limited by chip, not package.

BUK7277-55A Product data sheet

BUK7277-55A

N-channel TrenchMOS standard level FET



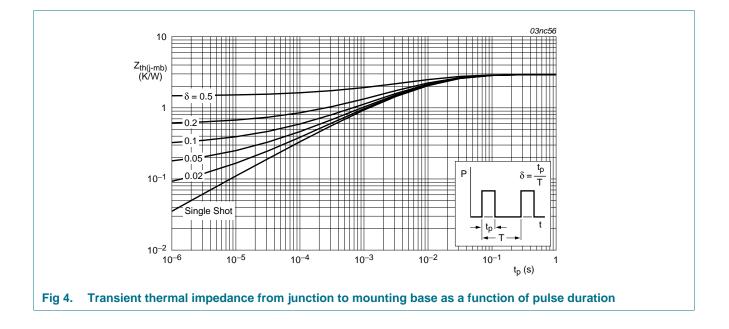
5. Thermal characteristics

Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	2.9	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint; FR4 board	-	71.4	-	K/W
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Product data sheet

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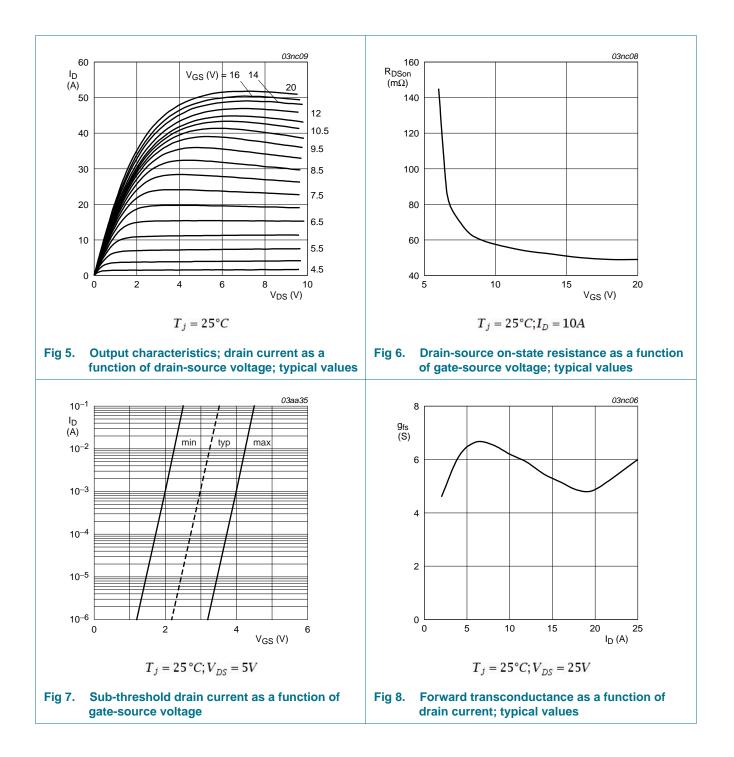


N-channel TrenchMOS standard level FET

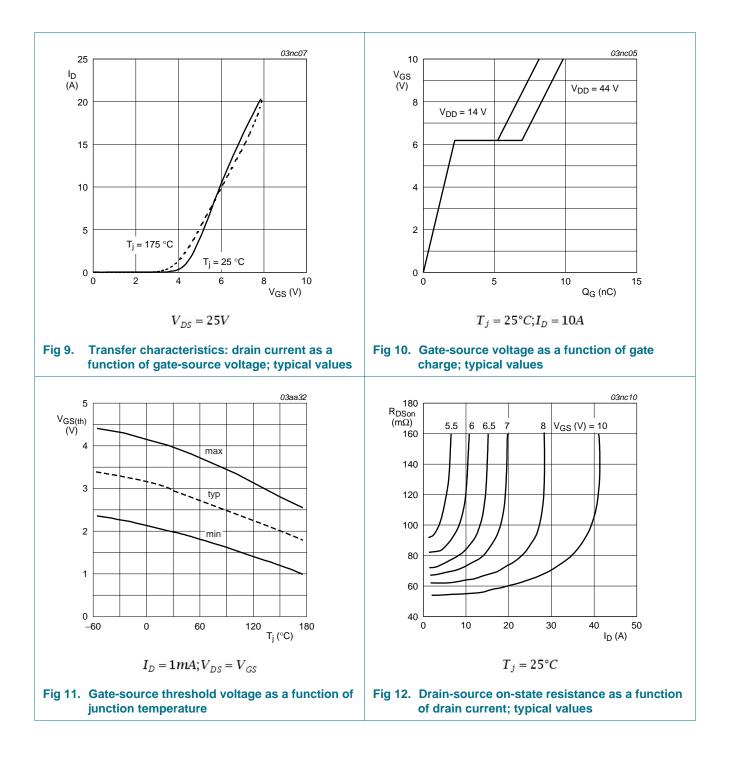
6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	55	-	-	V
breakdown voltage	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
V _{GS(th)}	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; see <u>Figure 11</u>	2	3	4	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 11</u>	-	-	4.4	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; see <u>Figure 11</u>	1	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; \text{ T}_{j} = 175 \text{ °C}$	-	-	500	μA
I _{GSS}	gate leakage current	V_{GS} = 20 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
R _{DSon} drain-source on-state resistance	drain-source on-state resistance	V _{GS} = 10 V; I _D = 10 A; T _j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	154	mΩ
		V _{GS} = 10 V; I _D = 10 A; T _j = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	65	77	mΩ
Dynamic	characteristics					
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	316	422	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 14}{\text{Figure } 14}$	-	92	110	pF
C _{rss}	reverse transfer capacitance		-	64	87	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	10	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	50	-	ns
t _{d(off)}	turn-off delay time		-	70	-	ns
t _f	fall time		-	40	-	ns
L _D	internal drain inductance	measured from drain lead from package to centre of die ; $T_j = 25 \text{ °C}$	-	2.5	-	nH
L _S	internal source inductance	measured from source lead from package to source bond pad ; $T_j = 25 \ ^{\circ}C$	-	7.5	-	nH
Source-d	rain diode					
V_{SD}	source-drain voltage	I _S = 10 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 15</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s};$	-	32	-	ns
Q _r	recovered charge	V_{GS} = -10 V; V_{DS} = 30 V; T_j = 25 °C	-	120	-	nC

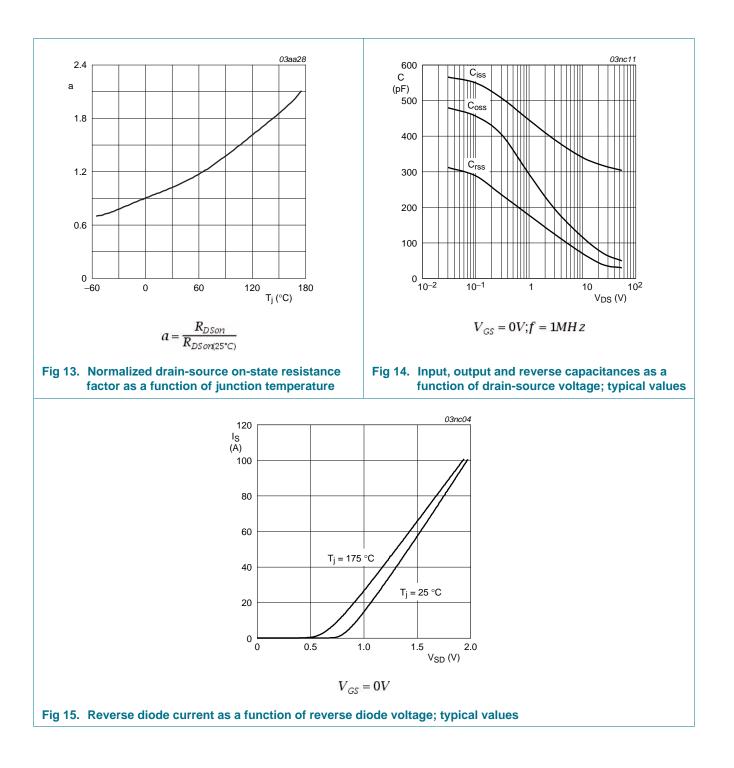
BUK7277-55A Product data sheet



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N-channel TrenchMOS standard level FET

7. Package outline

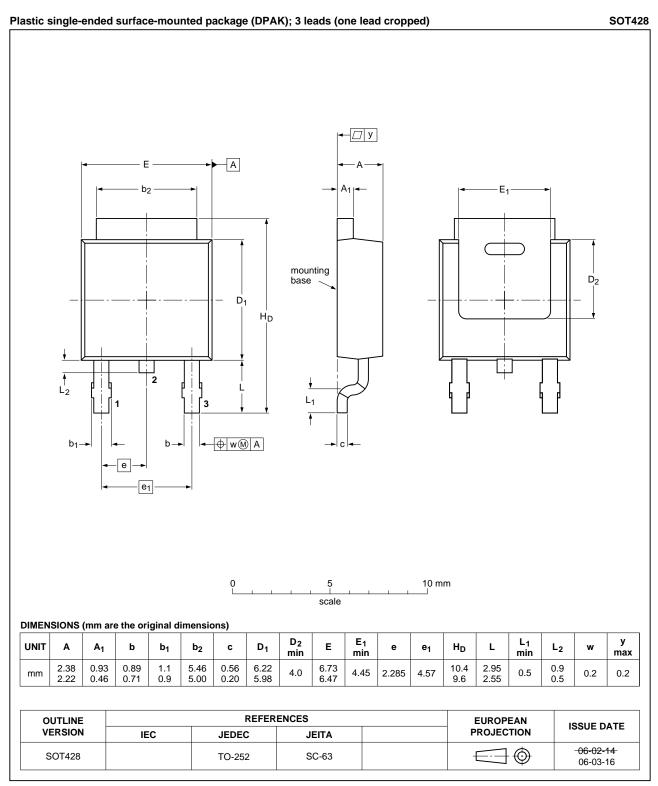


Fig 16. Package outline SOT428 (DPAK)

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Product data sheet

BUK7277-55A

9 of 13

N-channel TrenchMOS standard level FET

8. Revision history

Table 7. Revision	history				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7277-55A v.2	20110126	Product data sheet	-	BUK7277-55A v.1	
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 				
	 Legal texts hat 	ve been adapted to the new	company name where	appropriate.	
	 Various change 	les to content.			
BUK7277-55A v.1	20010201	Product specification	-	-	

N-channel TrenchMOS standard level FET

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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BUK7277-55A

N-channel TrenchMOS standard level FET

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N-channel TrenchMOS standard level FET

11. Contents

1	Product profile1
1.1	General description1
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Limiting values2
5	Thermal characteristics3
6	Characteristics5
7	Package outline9
8	Revision history10
9	Legal information
9.1	Data sheet status11
9.2	Definitions11
9.3	Disclaimers
9.4	Trademarks12
10	Contact information12

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